

FDB12N50F N-Channel UniFETTM FRFET[®] MOSFET 500 V, 11.5 A, 700 m Ω

Features

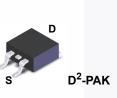
- $R_{DS(on)}$ = 590 m Ω (Typ.) @ V_{GS} = 10 V, I_D = 6 A
- Low Gate Charge (Typ. 21 nC)
- Low C_{rss} (Typ. 11 pF)
- 100% Avalanche Tested
- Improve dv/dt Capability
- RoHS Compliant

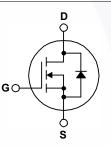
Applications

- Lighting
- Uninterruptible Power Supply
- AC-DC Power Supply

Description

UniFETTM MOSFET is Fairchild Semiconductor's high voltage MOSFET family based on planar stripe and DMOS technology. This MOSFET is tailored to reduce on-state resistance, and to provide better switching performance and higher avalanche energy strength. The body diode's reverse recovery performance of UniFET FRFET[®] MOSFET has been enhanced by lifetime control. Its t_{rr} is less than 100nsec and the reverse dv/dt immunity is 15V/ns while normal planar MOSFETs have over 200nsec and 4.5V/nsec respectively. Therefore, it can remove additional component and improve system reliability in certain applications in which the performance of MOSFET's body diode is significant. This device family is suitable for switching power converter applications such as power factor correction (PFC), flat panel display (FPD) TV power, ATX and electronic lamp balasts.





MOSFET Maximum Ratings T_C = 25°C unless otherwise noted.

Symbol		Parameter		FDB12N50FTM_WS	Unit
V _{DSS}	Drain to Source Voltage		500	V	
V _{GSS}	Gate to Source Voltage		±30	V	
I _D	Drain Current	- Continuous (T _C = 25 ^o C)		11.5	А
		- Continuous (T _C = 100 ^o C)		6.9	
I _{DM}	Drain Current	- Pulsed	(Note 1)	46	А
E _{AS}	Single Pulsed Avalanche Energy (Note 2)		(Note 2)	456	mJ
I _{AR}	Avalanche Current (No		(Note 1)	11.5	А
E _{AR}	Repetitive Avalanche Energy (Note		(Note 1)	16.5	mJ
dv/dt	Peak Diode Recovery dv/dt (Note 3)		(Note 3)	20	V/ns
P _D	Power Dissipation	(T _C = 25 ^o C)		165	W
		- Derate above 25°C		1.33	W/ºC
T _J , T _{STG}	Operating and Storage Temperature Range			-55 to +150	°C
TL	Maximum Lead Temperature for Soldering Purpose, 1/8" from Case for 5 Seconds		300	°C	

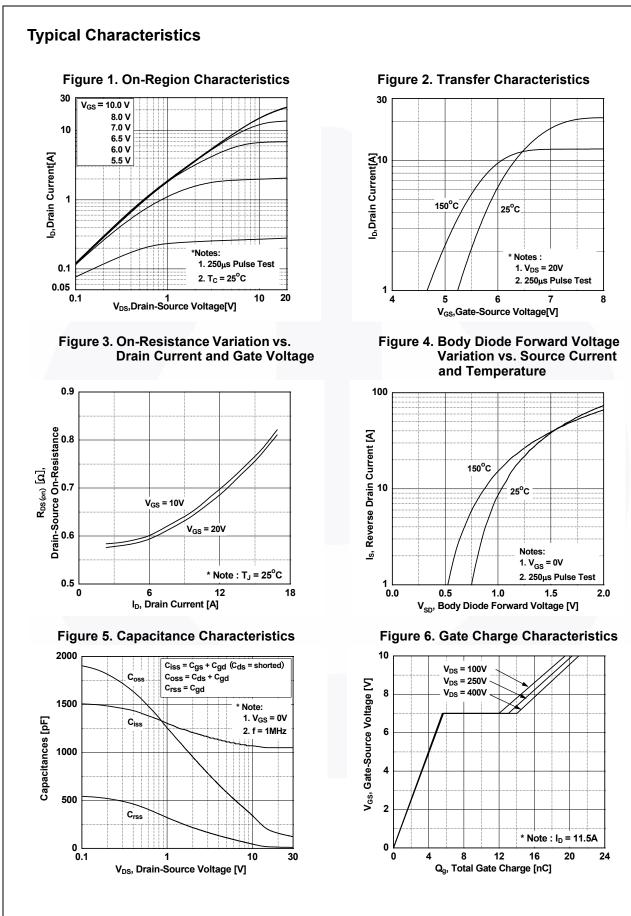
Thermal Characteristics

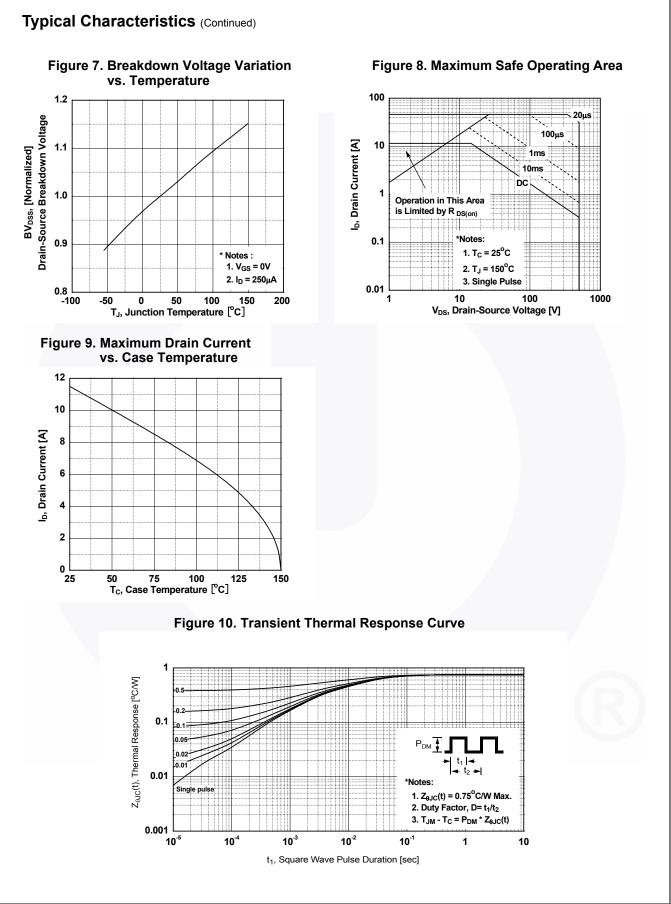
Symbol	Parameter	FQB12N50FTM_WS	Unit
$R_{\theta JC}$	Thermal Resistance, Junction to Case, Max	0.75	
Р	Thermal Resistance, Junction to Ambient (minimum pad of 2 oz copper), Max.	62.5	°C/W
$R_{ extsf{ heta}JA}$	Thermal Resistance, Junction to Ambient (1 in ² pad of 2 oz copper), Max.	40	

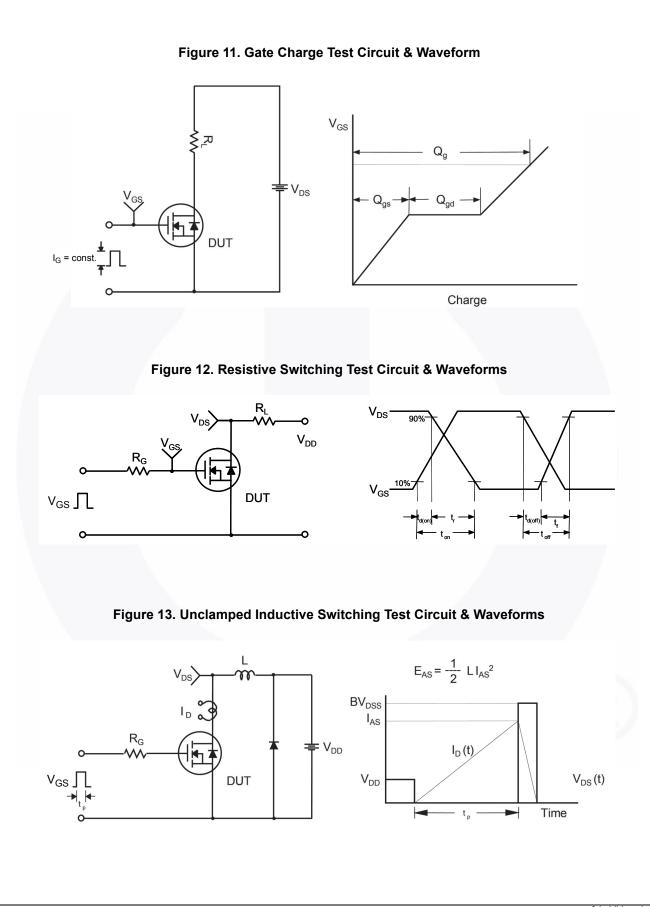
November 2013

FDB12N50FTM_WS	I _D = 25	330mm e noted. Test Conditions 0μΑ, V _{GS} = 0V, T _J = 25'	24mm Min.	Тур.	800 un Max.	its Unit
Parameter etics in to Source Breakdown Voltage akdown Voltage Temperature	I _D = 25	Test Conditions		Тур.	Max.	Unit
tics in to Source Breakdown Voltage akdown Voltage Temperature				Тур.	Max.	Unit
in to Source Breakdown Voltage akdown Voltage Temperature		0μΑ, V _{GS} = 0V, T _J = 25	°C 500			
akdown Voltage Temperature		0μΑ, V _{GS} = 0V, T _J = 25	0C E00			
			500	-	-	V
efficient	10 = 25	$I_D = 250 \mu A$, Referenced to $25^{\circ}C$		0.5	_	V/°C
	-	V _{DS} = 500V, V _{GS} = 0V			10	
o Gate Voltage Drain Current				-	-	μA
Gate to Body Leakage Current				-	±100	nA
					1	1
Gate Threshold Voltage				-		V
					0.7	Ω S
	VDS -	τον, η _D - ολ	-	12	-	5
cteristics						
t Capacitance	\/	V _{DS} = 25V, V _{GS} = 0V f = 1MHz		1050	1395	pF
out Capacitance				135	180	pF
			-			pF
-	Vpc =	V _{DS} = 400V, I _D = 11.5A V _{GS} = 10V				nC nC
				-		
		(Note 4)	9	-	nC
racteristics						
-On Delay Time			-	21	50	ns
-On Rise Time			-	45	100	ns
-Off Delay Time	R _G = 2	$R_{G} = 25\Omega$		50	110	ns
o-Off Fall Time		(Note 4) -	35	80	ns
oiode Characteristics						
	Diode Forwar	d Current	-	_	11.5	Α
			-	-	46	A
n to Source Diode Forward Voltage	e V _{GS} = (0V, I _{SD} = 11.5A	-	-	1.5	V
erse Recovery Time		$V_{GS} = 0V, I_{SD} = 11.5A$ $dI_F/dt = 100A/\mu s$		134	-	ns
erse Recovery Charge	dI _F /dt =			0.37	-	μΟ
	e to Body Leakage Current tics e Threshold Voltage ic Drain to Source On Resistance ward Transconductance exacteristics It Capacitance out Capacitance erse Transfer Capacitance I Gate Charge at 10V e to Source Gate Charge e to Drain "Miller" Charge cacteristics -On Delay Time -Off Delay Time -Off Pall Time Viode Characteristics imum Continuous Drain to Source Diode ros Source Diode Forward Voltage erse Recovery Time erse Recovery Charge	$V_{DS} = 4$ e to Body Leakage Current $V_{GS} = 3$ tics $V_{GS} = 3$ e Threshold Voltage $V_{GS} = 3$ ic Drain to Source On Resistance $V_{GS} = 3$ ward Transconductance $V_{DS} = 3$ ic Capacitance $V_{DS} = 3$ it Capacitance $V_{DS} = 3$ e to Source Gate Charge $V_{DS} = 3$ e to Source Gate Charge $V_{DS} = 3$ e to Drain "Miller" Charge $V_{DS} = 3$ racteristics $V_{DS} = 3$ -On Delay Time $V_{DD} = 3$ -On Rise Time $V_{DD} = 3$ -Off Delay Time $R_G = 2$ -Off Fall Time $R_G = 2$ viode Characteristics $R_G = 2$ imum Continuous Drain to Source Diode Forward Cun to Source Diode Forward Voltage $V_{GS} = 0$ erse Recovery Time $V_{GS} = 0$	VDS $= 400V, I_C = 125^{\circ}C$ a to Body Leakage Current $V_{GS} = \pm 30V, V_{DS} = 0V$ tics $V_{GS} = V_{DS}, I_D = 250\mu A$ a to Body Leakage Corrent $V_{GS} = V_{DS}, I_D = 250\mu A$ a to Drain to Source On Resistance $V_{GS} = 10V, I_D = 6A$ ward Transconductance $V_{DS} = 40V, I_D = 6A$ ward Transconductance $V_{DS} = 40V, I_D = 6A$ a to Capacitance $V_{DS} = 25V, V_{GS} = 0V$ a to Source Gate Charge $V_{DS} = 400V, I_D = 11.5A$ a to Source Gate Charge $V_{DS} = 400V, I_D = 11.5A$ a to Source Gate Charge $V_{DS} = 10V$ a to Source Gate Charge $V_{DS} = 250V, I_D = 11.5A$ a to Source Gate Charge $V_{DD} = 250V, I_D = 11.5A$ a to Drain "Miller" Charge $V_{DD} = 250V, I_D = 11.5A$ a coff Fall Time $V_{CS} = 0V, I_{SD} = 11.5A$ a coff Fall Time $V_{GS} = 0V, I_{SD} = 11.5A$ a to Source Diode Forward CurrentImum Continuous Drain to Source Diode Forward Currenta to Source Diode Forward Voltage $V_{GS} = 0V, I_{SD} = 11.5A$ a to Source Diode Forward Voltage $V_{GS} = 0V, I_{SD} = 11.5A$ a to Source Diode Forward Voltage $V_{GS} = 0V, I_{SD} = 11.5A$ a to Source Diode Forward Voltage $V_{GS} = 0V, I_{SD} = 11.5A$ a to Source Diode Forward Voltage $V_{GS} = 0V, I_{SD} = 11.5A$ a to Source Diode Forward Voltage $V_{GS} = 0V, I_{SD} = 11.5A$ a to Source Diode Forward Voltage $V_{GS} = 0V, I_{SD} = 11.5A$ a to Source Diode Forward Voltage $V_{GS} = 0V, I_{SD} = 11.5A$ a to Source Diode Forwar	VDS400V, $\Gamma_{C} = 125^{\circ}C$ -a to Body Leakage Current $V_{GS} = \pm 30V, V_{DS} = 0V$ -ticsVDS $= 30V, V_{DS} = 0V$ -a Threshold Voltage $V_{GS} = V_{DS}, I_D = 250\mu A$ 3.0ic Drain to Source On Resistance $V_{GS} = 10V, I_D = 6A$ -ward Transconductance $V_{DS} = 40V, I_D = 6A$ -etceristics $V_{DS} = 40V, I_D = 6A$ -etceristics $f = 1MHz$ -etceractionce $f = 1MHz$ -I Gate Charge at $10V$ $V_{DS} = 400V, I_D = 11.5A$ -e to Drain "Miller" Charge $V_{CS} = 10V$ -e to Drain "Miller" Charge $V_{DS} = 250V, I_D = 11.5A$ Off Delay Time $V_{DD} = 250V, I_D = 11.5A$ Off Fall Time $V_{OS} = 25\Omega$ -ender Characteristicsinum Continuous Drain to Source Diode Forward Current-in to Source Diode Forward Current-in to Source Diode Forward Voltage $V_{GS} = 0V, I_{SD} = 11.5A$ -erse Recovery Time $V_{GS} = 0V, I_{SD} = 11.5A$ -erse Recovery Time $V_{GS} = 0V, I_{SD} = 11.5A$ -erse Recovery Charge $dI_F/dt = 100A/\mu_S$ -	VDS400V, I_C = 125°Ca to Body Leakage Current $V_{GS} = \pm 30V, V_{DS} = 0V$ ticsa Threshold Voltage $V_{GS} = V_{DS}, I_D = 250\mu$ A3.0-ic Drain to Source On Resistance $V_{GS} = 10V, I_D = 6A$ -0.59ward Transconductance $V_{DS} = 40V, I_D = 6A$ -12icteristics-1050ict Capacitance $V_{DS} = 25V, V_{GS} = 0V$ -135icteristics-111I Gate Charge at 10V-21a to Drain "Miller" Charge $V_{DS} = 400V, I_D = 11.5A$ -6vonce Gate Charge $V_{DS} = 10V$ -216-9racteristics66	VDS = 4000', I_C = 125°C - - 100 e to Body Leakage Current V _{GS} = ±30V, V _{DS} = 0V - - ±100 tics - - - ±100 a Threshold Voltage V _{GS} = V _{DS} , I _D = 250µA 3.0 - 5.0 ic Drain to Source On Resistance V _{GS} = 10V, I _D = 6A - 0.59 0.7 ward Transconductance V _{DS} = 40V, I _D = 6A - 12 - etteristics - 112 - - tCapacitance V _{DS} = 25V, V _{GS} = 0V - 135 180 erse Transfer Capacitance F = 1MHz - 11 17 I Gate Charge at 10V V _{DS} = 400V, I _D = 11.5A - 6 - ot source Gate Charge V _{DS} = 400V, I _D = 11.5A - 6 - -On Dialy Time - 21 50 - 50 110 -On Rise Time V _{DD} = 250V, I _D = 11.5A - 45 100 -Off Eall Time V _{CD} = 250

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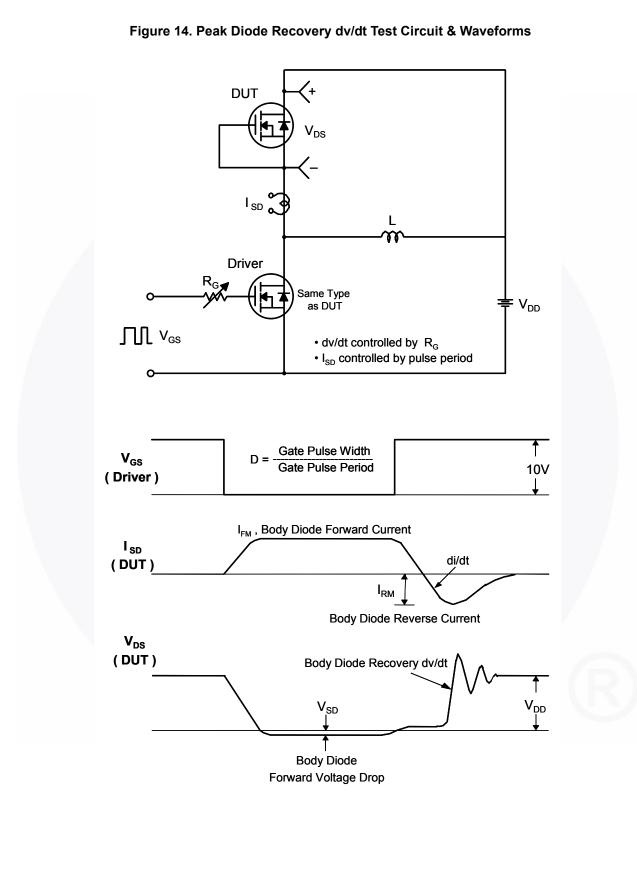


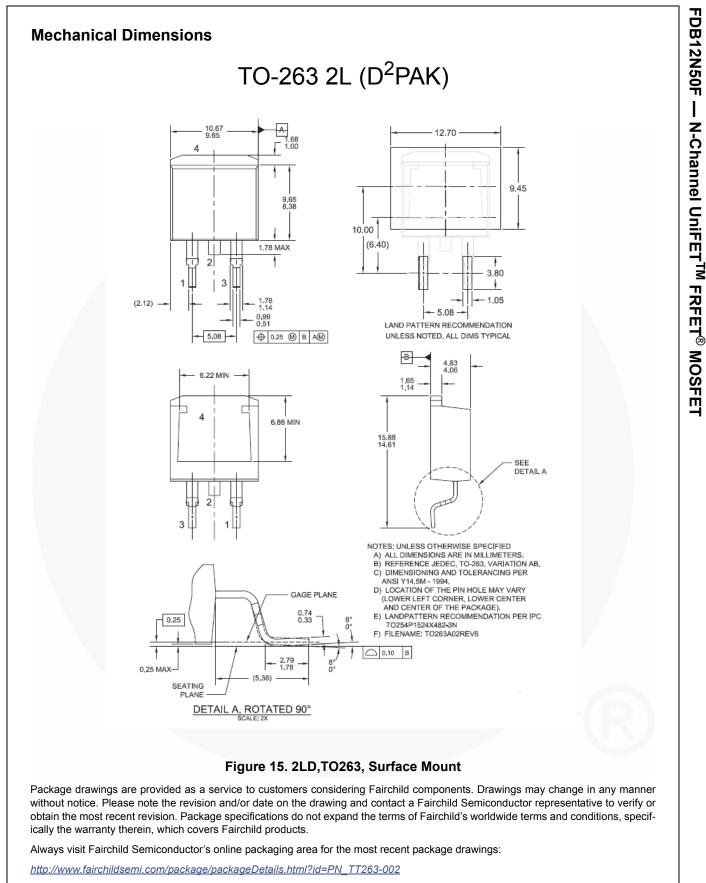


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Dimension in Millimeters



SEMICONDUCTOR

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